

# INTERNATIONAL STANDARD

# NORME INTERNATIONALE



INTERNATIONAL SPECIAL COMMITTEE ON RADIO INTERFERENCE  
COMITÉ INTERNATIONAL SPÉCIAL DES PERTURBATIONS RADIOÉLECTRIQUES

Limits and methods of measurement of radio disturbance characteristics of  
electrical lighting and similar equipment

Limites et méthodes de mesure des perturbations radioélectriques produites  
par les appareils électriques d'éclairage et les appareils analogues

ITU STANDARD PREVIEW  
(standards.iteh.ai)  
CISPR 15:2018  
<https://standards.iteh.ai/catalog/standards/sist/66821605-36a3-4629-b000-53602d9d765f/cispr-15-2018>





## THIS PUBLICATION IS COPYRIGHT PROTECTED

Copyright © 2018 IEC, Geneva, Switzerland

All rights reserved. Unless otherwise specified, no part of this publication may be reproduced or utilized in any form or by any means, electronic or mechanical, including photocopying and microfilm, without permission in writing from either IEC or IEC's member National Committee in the country of the requester. If you have any questions about IEC copyright or have an enquiry about obtaining additional rights to this publication, please contact the address below or your local IEC member National Committee for further information.

Droits de reproduction réservés. Sauf indication contraire, aucune partie de cette publication ne peut être reproduite ni utilisée sous quelque forme que ce soit et par aucun procédé, électronique ou mécanique, y compris la photocopie et les microfilms, sans l'accord écrit de l'IEC ou du Comité national de l'IEC du pays du demandeur. Si vous avez des questions sur le copyright de l'IEC ou si vous désirez obtenir des droits supplémentaires sur cette publication, utilisez les coordonnées ci-après ou contactez le Comité national de l'IEC de votre pays de résidence.

IEC Central Office  
3, rue de Varembe  
CH-1211 Geneva 20  
Switzerland

Tel.: +41 22 919 02 11  
[info@iec.ch](mailto:info@iec.ch)  
[www.iec.ch](http://www.iec.ch)

### About the IEC

The International Electrotechnical Commission (IEC) is the leading global organization that prepares and publishes International Standards for all electrical, electronic and related technologies.

### About IEC publications

The technical content of IEC publications is kept under constant review by the IEC. Please make sure that you have the latest edition, a corrigenda or an amendment might have been published.

#### IEC Catalogue - [webstore.iec.ch/catalogue](http://webstore.iec.ch/catalogue)

The stand-alone application for consulting the entire bibliographical information on IEC International Standards, Technical Specifications, Technical Reports and other documents. Available for PC, Mac OS, Android Tablets and iPad.

#### IEC publications search - [webstore.iec.ch/advsearchform](http://webstore.iec.ch/advsearchform)

The advanced search enables to find IEC publications by a variety of criteria (reference number, text, technical committee,...). It also gives information on projects, replaced and withdrawn publications.

#### IEC Just Published - [webstore.iec.ch/justpublished](http://webstore.iec.ch/justpublished)

Stay up to date on all new IEC publications. Just Published details all new publications released. Available online and also once a month by email.

#### Electropedia - [www.electropedia.org](http://www.electropedia.org)

The world's leading online dictionary of electronic and electrical terms, containing 21 000 terms and definitions in English and French, with equivalent terms in 16 additional languages. Also known as the International Electrotechnical Vocabulary (IEV) online.

#### IEC Glossary - [std.iec.ch/glossary](http://std.iec.ch/glossary)

67 000 electrotechnical terminology entries in English and French extracted from the Terms and Definitions clause of IEC publications issued since 2002. Some entries have been collected from earlier publications of IEC TC 37, 77, 86 and CISPR.

#### IEC Customer Service Centre - [webstore.iec.ch/csc](http://webstore.iec.ch/csc)

If you wish to give us your feedback on this publication or need further assistance, please contact the Customer Service Centre: [sales@iec.ch](mailto:sales@iec.ch).

### A propos de l'IEC

La Commission Electrotechnique Internationale (IEC) est la première organisation mondiale qui élabore et publie des Normes internationales pour tout ce qui a trait à l'électricité, à l'électronique et aux technologies apparentées.

### A propos des publications IEC

Le contenu technique des publications IEC est constamment revu. Veuillez vous assurer que vous possédez l'édition la plus récente, un corrigendum ou amendement peut avoir été publié.

#### Catalogue IEC - [webstore.iec.ch/catalogue](http://webstore.iec.ch/catalogue)

Application autonome pour consulter tous les renseignements bibliographiques sur les Normes internationales, Spécifications techniques, Rapports techniques et autres documents de l'IEC. Disponible pour PC, Mac OS, tablettes Android et iPad.

#### Recherche de publications IEC - [webstore.iec.ch/advsearchform](http://webstore.iec.ch/advsearchform)

La recherche avancée permet de trouver des publications IEC en utilisant différents critères (numéro de référence, texte, comité d'études,...). Elle donne aussi des informations sur les projets et les publications remplacées ou retirées.

#### IEC Just Published - [webstore.iec.ch/justpublished](http://webstore.iec.ch/justpublished)

Restez informé sur les nouvelles publications IEC. Just Published détaille les nouvelles publications parues. Disponible en ligne et aussi une fois par mois par email.

#### Electropedia - [www.electropedia.org](http://www.electropedia.org)

Le premier dictionnaire en ligne de termes électroniques et électriques. Il contient 21 000 termes et définitions en anglais et en français, ainsi que les termes équivalents dans 16 langues additionnelles. Egalement appelé Vocabulaire Electrotechnique International (IEV) en ligne.

#### Glossaire IEC - [std.iec.ch/glossary](http://std.iec.ch/glossary)

67 000 entrées terminologiques électrotechniques, en anglais et en français, extraites des articles Termes et Définitions des publications IEC parues depuis 2002. Plus certaines entrées antérieures extraites des publications des CE 37, 77, 86 et CISPR de l'IEC.

#### Service Clients - [webstore.iec.ch/csc](http://webstore.iec.ch/csc)

Si vous désirez nous donner des commentaires sur cette publication ou si vous avez des questions contactez-nous: [sales@iec.ch](mailto:sales@iec.ch).

# INTERNATIONAL STANDARD

# NORME INTERNATIONALE



INTERNATIONAL SPECIAL COMMITTEE ON RADIO INTERFERENCE  
COMITÉ INTERNATIONAL SPÉCIAL DES PERTURBATIONS RADIOÉLECTRIQUES

**Limits and methods of measurement of radio disturbance characteristics of electrical lighting and similar equipment**

**Limites et méthodes de mesure des perturbations radioélectriques produites par les appareils électriques d'éclairage et les appareils analogues**

INTERNATIONAL  
ELECTROTECHNICAL  
COMMISSION

COMMISSION  
ELECTROTECHNIQUE  
INTERNATIONALE

ICS 33.100.10

ISBN 978-2-8322-5648-0

**Warning! Make sure that you obtained this publication from an authorized distributor.  
Attention! Veuillez vous assurer que vous avez obtenu cette publication via un distributeur agréé.**

## INTERNATIONAL ELECTROTECHNICAL COMMISSION

---

**CISPR 15**  
 Edition 9.0 2018-05

**LIMITS AND METHODS OF MEASUREMENT  
 OF RADIO DISTURBANCE CHARACTERISTICS OF  
 ELECTRICAL LIGHTING AND SIMILAR EQUIPMENT**
**INTERPRETATION SHEET 1**

This interpretation sheet has been prepared by subcommittee CISPR F: Interference relating to household appliances tools, lighting equipment and similar apparatus, of IEC technical committee CISPR: International special committee on radio interference.

The text of this interpretation sheet is based on the following documents:

DISH	Report on voting
CIS/F/777/DISH	CIS/F/790/RVDISH

<https://standards.iteh.ai/catalog/standards/sist/b6829b05-56a5-4b23-bb6c-53602d9d765f/cispr-15-2018>

Full information on the voting for the approval of this interpretation sheet can be found in the report on voting indicated in the above table.

---

**CISPR 15 interpretation sheet on the worst-case mode of operation**
**Introduction**

Subclause 7.5 specifies the operating modes of lighting equipment that must be considered during an emission test. A few examples are given to support the explanation of what 'different operating modes' means. The list of examples is of course not exhaustive. Apparently, the example of 'colour shifting' is not clear enough and it is sometimes interpreted as if any possible colour and/or correlated colour temperature (CCT) setting that lighting equipment may produce shall be assessed during measurements. Many types of LED lighting may be set in many different colours and CCTs. Compared to other operational-mode related influence quantities such as light level regulation, flashing or radio communication, the risk of not capturing the maximum level of electromagnetic (EM) disturbances due to different colour or CCT settings is very small, provided that all channels of a LED driver used to change colour or CCT are operative. The 'colour shifting'-example was meant for example for a mode where the light output continuously switches from one colour to another with a certain repetition frequency (e.g. applied for entertainment, events etc.), instead of emitting a single stable colour and/or CCT.

## Question

What is the meaning of example 'colour shifting' as mode of operation to be considered during testing? What colour and/or colour temperature should be selected in case lighting equipment can be set in a wide range of colours and/or CCTs?

## Interpretation

The example 'colour shifting' in the first paragraph of 7.5 of CISPR 15:2018 must not be interpreted as if any possible colour and/or CCT setting that lighting equipment may produce shall be assessed during measurements.

Generally, according to 7.5 the worst case shall be found by prescanning every mode of operation over at least one repetition interval of the specific mode.

Alternatively, measurements can be performed using the setting(s) that are expected to produce the highest amplitude emissions relative to the limit; and, the reasons for the selection shall be given in the test report.

A reason could be that highest level of electromagnetic (EM) disturbances will be captured if all channels of a LED driver used to create different colours and/or CCTs are operative. The number of channels applied depends on the LED-driver/LED-light-source architecture. Often, maximum EM disturbances can be achieved by selecting a white colour and/or a CCT setting in the middle of the specified CCT range.

EXAMPLE Colour variation and CCT variation may be achieved using a 5-channel LED driver powering three LED strings for colour (RGB) setting and two cool white and warm white LED strings for CCT setting. Hence, in case the lighting equipment under test is capable to operate at different colours and/or CCTs, a white colour and/or a single CCT in the middle of the specified CCT range may be selected<sup>1</sup>.

[CISPR 15:2018](https://standards.iteh.ai/catalog/standards/sist/b6829b05-56a5-4b23-bb6c-53602d9d765f/cispr-15-2018)

<https://standards.iteh.ai/catalog/standards/sist/b6829b05-56a5-4b23-bb6c-53602d9d765f/cispr-15-2018>

---

<sup>1</sup> 7.4 of CISPR 15:2018, also still applies.

## CONTENTS

FOREWORD .....	7
1 Scope .....	9
2 Normative references .....	10
3 Terms, definitions and abbreviated terms .....	11
3.1 General.....	11
3.2 General terms and definitions .....	11
3.3 Terms and definitions related to equipment.....	12
3.4 Terms and definitions related to interfaces and ports .....	16
3.5 Abbreviated terms.....	18
4 Limits .....	20
4.1 General.....	20
4.2 Frequency ranges .....	20
4.3 Limits and methods for the assessment of wired network ports .....	21
4.3.1 Electric power supply interface .....	21
4.3.2 Wired network interfaces other than power supply .....	21
4.4 Limits and methods for the assessment of local wired ports .....	22
4.5 Limits and methods for the assessment of the enclosure port .....	23
4.5.1 General .....	23
4.5.2 Frequency range 9 kHz to 30 MHz .....	23
4.5.3 Frequency range 30 MHz to 1 GHz .....	24
5 Application of the limits.....	25
5.1 General.....	25
5.2 Identification of the interfaces subject to test.....	25
5.3 Application of limits to the interfaces.....	26
5.3.1 General .....	26
5.3.2 Conducted disturbance requirements for the wired network port .....	26
5.3.3 Conducted disturbance requirements for local wired ports .....	26
5.3.4 Radiated disturbance requirements for the enclosure port .....	26
5.3.5 Multiple interfaces of the same type.....	27
5.3.6 Interfaces that can be categorised as multiple types of ports .....	27
6 Product specific limit application requirements.....	28
6.1 General.....	28
6.2 Passive EUT .....	28
6.3 Rope lights .....	28
6.3.1 General .....	28
6.3.2 Requirements for rope lights.....	28
6.4 Modules .....	28
6.4.1 General .....	28
6.4.2 Modules having multiple applications .....	29
6.4.3 Internal modules .....	29
6.4.4 External modules.....	29
6.4.5 Single capped self-ballasted lamps.....	30
6.4.6 Double-capped self-ballasted lamps, double-capped lamp adapters, double-capped semi-luminaires and double-capped retrofit lamps used in fluorescent lamp luminaires .....	30
6.4.7 ELV lamps .....	30

6.4.8	Single-capped semi-luminaires .....	30
6.4.9	Independent igniters .....	30
6.4.10	Replaceable starters for fluorescent lamps .....	30
7	Operating and test conditions of the EUT .....	31
7.1	General .....	31
7.2	Switching .....	31
7.3	Supply voltage and frequency .....	31
7.4	Rated lamp load and light regulation .....	31
7.5	Operating modes .....	31
7.6	Ambient conditions .....	32
7.7	Lamps .....	32
7.7.1	Type of lamps used in lighting equipment .....	32
7.7.2	Ageing times .....	32
7.8	Stabilization times .....	32
7.9	Operation and loading of wired interfaces .....	32
7.9.1	General .....	32
7.9.2	Interface intended for a continuous signal or data transmission .....	32
7.9.3	Interface not intended for a continuous signal or data transmission .....	33
7.9.4	Load .....	33
8	Methods of measurement of conducted disturbances .....	33
8.1	General .....	33
8.2	Measurement instrumentation and methods .....	33
8.3	Electrical power supply interface disturbance measurement .....	34
8.4	Disturbance measurement of wired network interfaces other than power supply .....	34
8.5	Local wired port disturbance measurement .....	35
8.5.1	Electrical power supply of ELV lamps .....	35
8.5.2	Other than electrical power supply of ELV lamps .....	35
9	Methods of measurement of radiated disturbances .....	35
9.1	General .....	35
9.2	Intentional wireless transmitters .....	35
9.3	Measurement instrumentation and methods .....	36
9.3.1	General .....	36
9.3.2	LLAS radiated disturbance measurement 9 kHz to 30 MHz .....	36
9.3.3	Loop antenna radiated disturbance measurement 9 kHz to 30 MHz .....	37
9.3.4	Radiated disturbance measurement 30 MHz to 1 GHz .....	37
10	Compliance with this document .....	38
11	Measurement uncertainty .....	38
12	Test report .....	38
Annex A (normative) Product specific application notes referring to particular measurement set-ups or operating conditions .....		42
A.1	Single-capped self-ballasted lamps .....	42
A.1.1	Arrangement for conducted disturbance measurements .....	42
A.1.2	Arrangement for radiated disturbance measurements .....	42
A.2	Semi-luminaires .....	42
A.3	Rope lights .....	42
A.3.1	Preparation of the EUT .....	42
A.3.2	Arrangement for conducted disturbance measurements .....	43

A.3.3	Arrangement for radiated disturbance measurements .....	43
A.4	Double-capped lamp adapters, double-capped self-ballasted lamps, double-capped semi-luminaires and double-capped retrofit lamps used in fluorescent lamp luminaires .....	43
A.4.1	For application in linear luminaires with electromagnetic controlgear .....	43
A.4.2	For application in linear luminaires with electronic controlgear .....	43
A.4.3	For application in other than linear luminaires .....	43
A.4.4	Measurement methods .....	43
A.5	ELV lamps .....	44
A.5.1	Conducted disturbance test .....	44
A.5.2	Radiated disturbance tests .....	44
A.6	Independent igniters .....	44
Annex B (normative)	Test arrangements for conducted disturbance measurements .....	50
B.1	General.....	50
B.2	Arrangement of cables connected to interfaces of wired network ports.....	50
B.2.1	Arrangements of electric power supply cables .....	50
B.2.2	Arrangement of other than electric power supply cables .....	50
B.3	Arrangement of cables connected to interfaces of local wired ports.....	51
B.3.1	General .....	51
B.3.2	Cables of local-wired ports indirectly connected to a network .....	51
B.3.3	Cables of local-wired ports other than the type mentioned in B.3.2 .....	51
B.3.4	Power-supply cables of an ELV lamp.....	52
B.3.5	Arrangement of measurement probes.....	52
B.4	Loading and termination of cables.....	52
B.5	Luminaires .....	52
B.6	Modules.....	53
Annex C (normative)	Test arrangements for radiated disturbance measurements .....	57
C.1	General.....	57
C.2	Arrangements of electric power supply cables.....	57
C.3	Arrangement of cables other than electric power supply cables.....	57
C.4	Arrangements of EUT, auxiliary equipment and associated equipment.....	57
C.4.1	General .....	57
C.4.2	EUT arrangements for table-top, wall-mounted or ceiling-mounted applications .....	57
C.4.3	EUT arrangements for floor-standing and pole-mounted applications.....	57
C.5	Loading and termination of cables.....	57
Annex D (informative)	Examples of application of limits and test methods.....	61
D.1	General.....	61
D.2	Case 1: Power controlgear with remote battery connection .....	61
D.2.1	EUT description .....	61
D.2.2	Interfaces, ports and limits.....	61
D.3	Case 2: Universal presence and light detector .....	62
D.3.1	EUT description.....	62
D.3.2	Interfaces, ports and limits.....	62
D.4	Case 3: Driver with three load interfaces.....	64
D.4.1	EUT description .....	64
D.4.2	Interfaces, ports and limits.....	64
D.5	Case 4: Ethernet powered OLED .....	66
D.5.1	EUT description.....	66



D.5.2	Interfaces, ports and limits.....	66
D.6	Case 5: Stand-alone occupancy-daylight sensor .....	66
D.6.1	EUT description .....	66
D.6.2	Interfaces, ports and limits.....	67
Annex E (informative)	Statistical considerations in the determination of EMC compliance of mass-produced products .....	68
E.1	General.....	68
E.2	Test method based on a general margin to the limit .....	68
E.3	Test method based on the non-central t-distribution .....	69
E.3.1	Practical implementation by using frequency sub-ranges .....	69
E.3.2	Frequency sub-ranges .....	70
E.3.3	Data distortion occurring at a sub-range boundary.....	71
E.4	Test method based on the binomial distribution.....	71
E.5	Application of larger sample size.....	72
Bibliography.....		73
Figure 1 – EMC-ports of an EUT .....		18
Figure 2 – Generic depiction of the definitions of test-, ancillary-, auxiliary- and associated equipment w.r.t. EUT and the test/measurement environment (definitions given in CISPR 16-2-3) .....		20
Figure 3 – EUT and its physical interfaces .....		39
Figure 4 – Decision process on the application of limits to the EUT.....		40
Figure 5 – Example of a host system with different types of modules .....		41
Figure A.1 – Reference luminaire for double-capped lamp adapter, double-capped self-ballasted lamp, double-capped semi-luminaire and double-capped retrofit lamp used in linear fluorescent lamp luminaires (see A.4.1).....		45
Figure A.2 – Conical metal housing for single capped lamps (see A.1.1).....		46
Figure A.3 – Arrangements for conducted disturbance measurements from non-restricted ELV lamps (see A.5.1).....		47
Figure A.4 – Arrangements for conducted disturbance measurements from restricted ELV lamps (see A.5.1) .....		48
Figure A.5 – Hose-clamp reference luminaire for self-ballasted lamps with a GU10 bayonet cap (see A.1.1).....		49
Figure A.6 – Support plate for arranging long cables and rope lights (see 9.3.2, Clauses A.3 and B.3) .....		49
Figure B.1 – Circuit for measuring conducted disturbances from a luminaire (Figure B.1a), an internal/mounted/replaceable module (Figure B.1b) and a single capped self-ballasted or independent non-gas-discharge lamp Figure B.1c) .....		54
Figure B.2 – Circuit for measuring conducted disturbances from an external module .....		55
Figure B.3 – Measuring arrangements for conducted disturbances (see Clause B.5).....		56
Figure C.1 – EUT arrangement of ceiling-, wall-mounted and table-top applications during the radiated (OATS, SAC or FAR) disturbance measurement .....		58
Figure C.2 – EUT arrangement of floor-standing and pole-mounted applications during the radiated (OATS, SAC or FAR) disturbance measurement.....		59
Figure C.3 – Example of arrangement of a luminaire during the radiated (OATS, SAC or FAR) disturbance measurement.....		59
Figure C.4 – Example of arrangement of an internal module during the radiated (OATS, SAC or FAR) disturbance measurement .....		60

Figure C.5 – Example of arrangement of an external module during the radiated (OATS, SAC or FAR) disturbance measurement ..... 60

Figure D.1 – Case 1 EUT ..... 61

Figure D.2 – Case 2 EUT ..... 63

Figure D.3 – Case 3 EUT ..... 65

Figure D.4 – Case 4 EUT ..... 66

Figure D.5 – Case 5 EUT ..... 67

Figure E.1 – Illustration of difficulties in case the maximum value of the disturbance is at the boundary of a sub-range ..... 71

  

Table 1 – Disturbance voltage limits at the electric power supply interface ..... 21

Table 2 – Disturbance voltage limits at wired network interfaces other than power supply ..... 21

Table 3 – Disturbance current limits at wired network interfaces other than power supply ..... 22

Table 4 – Disturbance voltage limits of local wired ports: electrical power supply interface of non-restricted ELV lamps ..... 22

Table 5 – Disturbance voltage limits at local wired ports: local wired ports other than electrical power supply interface of ELV lamp ..... 23

Table 6 – Disturbance current limits at local wired ports: local wired ports other than electrical power supply interface of ELV lamp ..... 23

Table 7 – Maximum EUT dimension that can be used for testing using LLAS with different diameters ..... 24

Table 8 – LLAS radiated disturbance limits in the frequency range 9 kHz to 30 MHz ..... 24

Table 9 – Loop antenna radiated disturbance limits in the frequency range 9 kHz to 30 MHz for equipment with a dimension > 1,6 m ..... 24

Table 10 – Radiated disturbance limits and associated measurement methods in the frequency range 30 MHz to 1 GHz ..... 25

Table 11 – Overview of standardized conducted disturbance measurement methods ..... 34

Table 12 – Overview of standardized radiated disturbance measurement methods ..... 36

Table D.1 – Case 1: Summary of interfaces, applicable ports and limits ..... 62

Table D.2 – Case 2 – Application 1: Summary of interfaces, applicable ports and limits ..... 63

Table D.3 – Case 2 – Application 2: Summary of interfaces, applicable ports and limits ..... 64

Table D.4 – Case 3: Summary of interfaces, applicable ports and limits ..... 65

Table D.5 – Case 4: Summary of interfaces, applicable ports and limits ..... 66

Table D.6 – Case 5: Summary of interfaces, applicable ports and limits ..... 67

Table E.1 – General margin to the limit for statistical evaluation ..... 69

Table E.2 – Sample size and corresponding  $k$  factor in a non-central t-distribution ..... 70

Table E.3 – Application of the binomial distribution ..... 71

## INTERNATIONAL ELECTROTECHNICAL COMMISSION

## INTERNATIONAL SPECIAL COMMITTEE ON RADIO INTERFERENCE

---

**LIMITS AND METHODS OF MEASUREMENT OF  
RADIO DISTURBANCE CHARACTERISTICS OF  
ELECTRICAL LIGHTING AND SIMILAR EQUIPMENT****FOREWORD**

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
- 2) The formal decisions or agreements of IEC on technical matters express, as nearly as possible, an international consensus of opinion on the relevant subjects since each technical committee has representation from all interested IEC National Committees.
- 3) IEC Publications have the form of recommendations for international use and are accepted by IEC National Committees in that sense. While all reasonable efforts are made to ensure that the technical content of IEC Publications is accurate, IEC cannot be held responsible for the way in which they are used or for any misinterpretation by any end user.
- 4) In order to promote international uniformity, IEC National Committees undertake to apply IEC Publications transparently to the maximum extent possible in their national and regional publications. Any divergence between any IEC Publication and the corresponding national or regional publication shall be clearly indicated in the latter.
- 5) IEC itself does not provide any attestation of conformity. Independent certification bodies provide conformity assessment services and, in some areas, access to IEC marks of conformity. IEC is not responsible for any services carried out by independent certification bodies.
- 6) All users should ensure that they have the latest edition of this publication.
- 7) No liability shall attach to IEC or its directors, employees, servants or agents including individual experts and members of its technical committees and IEC National Committees for any personal injury, property damage or other damage of any nature whatsoever, whether direct or indirect, or for costs (including legal fees) and expenses arising out of the publication, use of, or reliance upon, this IEC Publication or any other IEC Publications.
- 8) Attention is drawn to the Normative references cited in this publication. Use of the referenced publications is indispensable for the correct application of this publication.
- 9) Attention is drawn to the possibility that some of the elements of this IEC Publication may be the subject of patent rights. IEC shall not be held responsible for identifying any or all such patent rights.

International Standard CISPR 15 has been prepared by subcommittee CIS/F: Interference relating to household appliances tools, lighting equipment and similar apparatus, of IEC technical committee CISPR: International special committee on radio interference.

This ninth edition cancels and replaces the eighth edition published in 2013 and its Amendment 1:2015. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) full editorial revision and restructuring;
- b) the restriction to mains and battery operation is deleted in the scope;
- c) radiated disturbance limits in the frequency range 300 MHz to 1 GHz have been introduced;

- d) the load terminals limits and the CDNE (alternative to radiated emissions) limits have changed;
- e) deletion of the insertion-loss requirements and the associated Annex A;
- f) introduction of three basic ports: wired network ports, local wired ports and the enclosure port;
- g) introduction of a more technology-independent approach;
- h) replacement of Annex B (CDNE) by appropriate references to CISPR 16-series of standards;
- i) modified requirements for the metal holes of the conical housing;
- j) new conducted disturbance measurement method for GU10 self-ballasted lamp;
- k) addition of current probe measurement method and limits for various types of ports (in addition to voltage limits and measurement methods);
- l) introduction of the term 'module' (instead of independent auxiliary) and requirements for measurement of modules using a host (reference) system;
- m) modified specifications for stabilization times of EUTs;
- n) for large EUT (> 1,6 m), addition of the magnetic field measurement method using a 60 cm loop antenna at 3 m distance (method from CISPR 14-1) as an alternative to the 3 m and 4 m LAS.

The text of this International Standard is based on the following documents:

FDIS Report on voting	
CIS/F/733/FDIS	CIS/F/736/RVD

Full information on the voting for the approval of this International Standard can be found in the report on voting indicated in the above table.

<https://standards.iteh.ai/catalog/standards/sist/b6829b05-56a5-4b23-bb6c-53602d9d765f/cispr-15-2018>

This document has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this document will remain unchanged until the stability date indicated on the IEC website under "http://webstore.iec.ch" in the data related to the specific document. At this date, the document will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended.

The contents of the interpretation sheet of November 2019 have been included in this copy.

**IMPORTANT – The 'colour inside' logo on the cover page of this publication indicates that it contains colours which are considered to be useful for the correct understanding of its contents. Users should therefore print this document using a colour printer.**

# LIMITS AND METHODS OF MEASUREMENT OF RADIO DISTURBANCE CHARACTERISTICS OF ELECTRICAL LIGHTING AND SIMILAR EQUIPMENT

## 1 Scope

This document applies to the emission (radiated and conducted) of radiofrequency disturbances from:

- lighting equipment (3.3.16);
- the lighting part of multi-function equipment where this lighting part is a primary function;

NOTE 1 Examples are lighting equipment with visible-light communication, entertainment lighting.

- UV and IR radiation equipment for residential and non-industrial applications;
- advertising signs;

NOTE 2 Examples are neon tube advertising signs.

- decorative lighting;
- emergency signs.

Excluded from the scope of this document are:

- components or modules intended to be built into lighting equipment and which are not user-replaceable;

NOTE 3 See CISPR 30 (all parts) for built-in control gear.

- lighting equipment operating in the ISM frequency bands (as defined in Resolution 63 (1979) of the ITU Radio Regulation);
- lighting equipment for aircraft and airfield facilities (runways, service facilities, platforms);
- video signs;
- installations;
- equipment for which the electromagnetic compatibility requirements in the radio-frequency range are explicitly formulated in other CISPR standards, even if they incorporate a built-in lighting function.

NOTE 4 Examples of exclusions are:

- equipment with built-in lighting devices for display back lighting, scale illumination and signaling;
- SSL-displays;
- range hoods, refrigerators, freezers;
- photocopiers, projectors;
- lighting equipment for road vehicles (in scope of CISPR 12).

The frequency range covered is 9 kHz to 400 GHz. No measurements need to be performed at frequencies where no limits are specified in this document.

Multi-function equipment which is subjected simultaneously to different clauses of this document and/or other standards need to meet the provisions of each clause/standard with the relevant functions in operation.

For equipment outside the scope of this document and which includes lighting as a secondary function, there is no need to separately assess the lighting function against this document, provided that the lighting function was operative during the assessment in accordance with the applicable standard.

NOTE 5 Examples of equipment with a secondary lighting function can be range hoods, fans, refrigerators, freezers, ovens and TV with ambient lighting.

The radiated emission requirements in this document are not intended to be applicable to the intentional transmissions from a radio transmitter as defined by the ITU, nor to any spurious emissions related to these intentional transmissions.

Within the remainder of this document, wherever the term "lighting equipment" or "EUT" is used, it is meant to be the electrical lighting and similar equipment falling in the scope of this document as specified in this clause.

## 2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 60038, *IEC standard voltages*

IEC 60050-161, *International Electrotechnical Vocabulary (IEV) – Chapter 161: Electromagnetic compatibility*

IEC 60050-845:1987, *International Electrotechnical Vocabulary – Chapter 845: Lighting*

IEC 60061-1, *Lamp caps and holders together with gauges for the control of interchangeability and safety – Part 1: Lamp caps*

IEC 60081, *Double-capped fluorescent lamps – Performance specifications*

IEC 60598-1:2014, *Luminaires – Part 1: General requirements and tests*  
IEC 60598-1:2014/AMD1:2017

IEC 60921, *Ballasts for tubular fluorescent lamps – Performance requirements*

IEC 61000-4-20:2010, *Electromagnetic compatibility (EMC) – Part 4-20: Testing and measurement techniques – Emission and immunity testing in transverse electromagnetic (TEM) waveguides*

IEC 61195, *Double-capped fluorescent lamps – Safety specifications*

IEC 62504:2014, *General lighting – Light emitting diode (LED) products and related equipment – Terms and definitions*

CISPR 16-1-1:2015, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 1-1: Radio disturbance and immunity measuring apparatus – Measuring apparatus*

CISPR 16-1-2:2014, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 1-2: Radio disturbance and immunity measuring apparatus – Coupling devices for conducted disturbance measurements*

CISPR 16-1-4:2010, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 1-4: Radio disturbance and immunity measuring apparatus – Antennas and test sites for radiated disturbance measurements*

CISPR 16-1-4:2010/AMD1:2012  
CISPR 16-1-4:2010/AMD2:2017

CISPR 16-2-1:2014, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 2-1: Methods of measurement of disturbances and immunity – Conducted disturbance measurements*  
CISPR 16-2-1:2014/AMD1:2017

CISPR 16-2-3:2016, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 2-3: Methods of measurement of disturbances and immunity – Radiated disturbance measurements*

CISPR 16-4-2:2011, *Specification for radio disturbance and immunity measuring apparatus and methods – Part 4-2: Uncertainties, statistics and limit modelling – Measurement instrumentation uncertainty*  
CISPR 16-4-2:2011/AMD1:2014

CISPR TR 30-1:2012, *Test method on electromagnetic emissions – Part 1: Electronic control gear for single- and double-capped fluorescent lamps*

CISPR 32:2015, *Electromagnetic compatibility of multimedia equipment – Emission requirements*

ISO/IEC 17025:2005<sup>1</sup>, *General requirements for the competence of testing and calibration laboratories*

### 3 Terms, definitions and abbreviated terms

#### 3.1 General

For the purposes of this document, the terms and definitions given in IEC 60050-161, IEC 62504, IEC 60050-845 and the following apply.

ISO and IEC maintain terminological databases for use in standardization at the following addresses:

- IEC Electropedia: available at <http://www.electropedia.org/>
- ISO Online browsing platform: available at <http://www.iso.org/obp>

#### 3.2 General terms and definitions

##### 3.2.1

##### **base of the luminaire**

mounting surface of the luminaire in normal use, usually the side opposite of the optical window

##### 3.2.2

##### **clock frequency**

fundamental frequency of any signal used in the EUT excluding those generated inside an integrated circuit (IC) and which are solely used inside the same IC without being accessible outside that IC, and excluding those used exclusively for radio transmission or radio receiving functions

Note 1 to entry: High frequencies are often generated inside integrated circuits (IC) by phase-locked-loop (PLL) circuits from lower clock oscillator frequencies outside the IC.

---

<sup>1</sup> This edition was replaced by ISO/IEC 17025:2017 but the listed edition applies.